

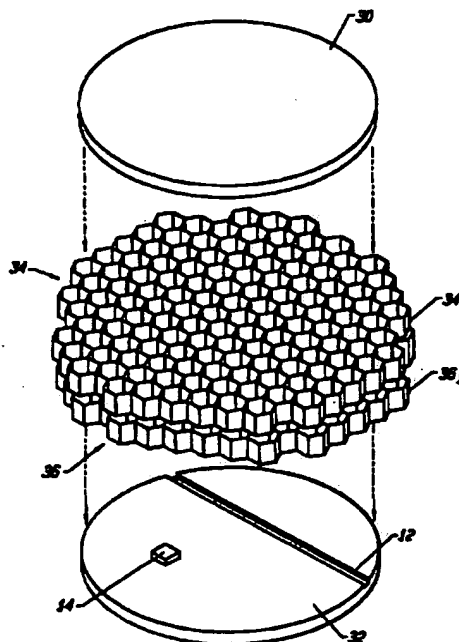
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(54) Title: MULTIPLE TIER COLLIMATOR SYSTEM FOR ENHANCED STEP COVERAGE AND UNIFORMITY**(57) Abstract**

A collimator system for use in PVD sputtering of semiconductor wafers having multiple tiers provided between a target and wafer substrate. The collimator system prevents target atoms from contacting the wafer at substantially oblique angles, thereby providing good step coverage uniformity over the surface of the wafer. Additionally, the presence of more than one tier prevents localized build-up of target atoms that occurs in conventional single tier collimators, thereby providing good flat coverage uniformity over the surface of the wafer.



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MULTIPLE TIER COLLIMATOR SYSTEM FOR
ENHANCED STEP COVERAGE AND UNIFORMITY

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CROSS REFERENCE TO RELATED SUBJECT MATTER

The present invention is related to currently pending U.S. Application Serial No. 08/316,090, entitled "PVD SPUTTER SYSTEM HAVING NONPLANAR TARGET
10 CONFIGURATION AND METHODS FOR OPERATING SAME" by Krivokapic et al., filed September 30, 1994, which application is incorporated by reference herein in its entirety.

Additionally, the following publications are
15 believed to be related to the present application and are cited here for purposes of reference:

(A) D. S. Bang. et al, "Modeling of Ti Physical Vapor Deposition Systems", IEEE International Workshop on Numerical Modeling of Processes and Devices for Integrated Circuits (NUPAD V, Honolulu) June 1994, pp
20 41-44;

(B) D. S. Bang. et al, "Profile Modeling of Collimated Ti Physical Vapor Deposition", 10th Symposium on Plasma Processing, Electro Chemical
25 Society, San Francisco, May 1994; and

(C) G. Box and N. Draper, "Empirical Model Building and Response Surfaces", John Wiley & Son, New York 1987.

BACKGROUND

5 Field of the Invention

The invention is generally directed to physical vapor deposition ("PVD") sputter systems. The invention is more specifically related to a multiple tier collimator system for use in PVD sputtering during the fabrication of semiconductor devices wherein it is desirable to obtain a combination of uniform deposition thickness, high deposition rate, and good step coverage.

Description of the Related Art

15 PVD sputtering is used within semiconductor processing and other arts for depositing metal films and the like onto substrate surfaces.

The substrate (e.g., a semiconductor wafer) is typically a planar disk that is positioned, face-down at the top of a vacuum plasma chamber.

20 A planar target is further typically positioned face-up within the chamber, in spaced apart and symmetrical counterfacing relation with the substrate. In older sputter systems the target was on top and the

substrate on the bottom. The substrate-on-top versus on-bottom orientation relates to keeping the substrate surface clean and is not directly related to the present invention. For purposes of consistency, the
5 older configuration with the substrate on the bottom will be shown, but it is to be understood that other orientations are fully within the contemplation of this invention.

The target is made of the material that is to be
10 sputter deposited onto the substrate surface. Examples include, but are not limited to, metals such as aluminum (Al), titanium (Ti), copper (Cu) and alloys or compounds of these materials.

Fundamentally, PVD sputtering involves bombarding
15 the surface of a target material to be deposited as the film with electrostatically accelerated argon ions. Generally, electric fields are used to accelerate ions in the plasma gas, causing them to impinge on the target surface. As a result of momentum transfer,
20 atoms and electrons are dislodged from the target surface in an area known as the erosion region. The dislodged particles follow a generally linear trajectory from their point of emission on the target surface to a collision point on the counterfacing
25 surface of the substrate. Physical adhesion mechanisms

cause the target particles to bond to the surface of the substrate, thereby forming a film on the substrate.

The physical dimensions and positionings of the substrate and target play important roles in determining rate of deposition and the uniformity of the deposited film. The distribution of emission-inducing energy across the target also plays a role.

Ideally, the target should be very wide relative to the substrate so that the target represents an infinite source plane to the particle-receiving face of the substrate. In a such a situation, if the particle receiving face of the substrate is perfectly planar and parallel to the target, every point on the substrate receiving face will receive the same contribution of deposition particles and film thickness will be uniform across the entire substrate.

Unfortunately this ideal arrangement is not possible in practical implementations of PVD sputter chambers. The target has a finite size that is usually the same order of magnitude as that of the substrate. Non-uniformities develop across the substrate for characteristics such as deposition film thickness and deposition rate due to boundary conditions. Non-uniformities in the substrate may also result from non-uniform target erosion.

In the fabrication of semiconductor devices, the substrate surface is often not perfectly planar. Nonlinear features such as channels and mesas are typically found on the semiconductor substrate. It is often desirable to coat the sidewalls and/or bottoms of each channel or mesa with a layer of deposition material having a prescribed thickness. However, the linear nature of the trajectories followed by the emitted target particles in PVD systems create shadow effects. Not every portion of the substrate surface receives the same amount of target material at the same rate in the case where the substrate surface includes nonlinearities such as channels or mesas.

The term, "channel" is used herein in a broad sense to include features in semiconductor devices and the like such as contact vias, trenches and other depressions which are to be fully or partially filled with deposition material. A channel 12 in wafer 10 is shown on Figs 1-3.

The term, "mesa" is similarly used herein in a broad sense to include any device feature rising above a surrounding plane where the feature and/or its surrounding plane are to be coated with deposition material. A mesa 14 in wafer 10 is shown on Figs. 1-3

The term, "step coverage" is used herein in a qualitative sense to refer to the ability to coat one

or more sidewalls or bottom of a channel or mesa to a desired thickness. The term, "step coverage" is further used herein in a quantitative sense to refer to the ratio of film thickness at the bottom center or top center of a channel or mesa, respectively, relative to the general film thickness of the planar regions of the wafer.

The term, "step coverage uniformity" is used herein in a quantitative sense to mean the statistical standard deviation (σ) of step coverage across a given substrate.

The term, "flat coverage uniformity" is used herein in a quantitative sense to mean the statistical standard deviation (σ) of film thickness across a given substrate taking into consideration only substantially planar regions (not step regions) of the substrate surface.

The term, "bottom coverage uniformity" is used herein in a quantitative sense to mean the statistical standard deviation (σ) of film thickness across a given substrate taking into consideration only regions at the bottom of channels or mesas.

It is desirable in PVD sputtering to control the path of the sputtered target atoms to travel substantially perpendicularly between the target and the wafer substrate. Perpendicular travel of the

target atoms yields an optimal step coverage, i.e., the ratio of film thickness at the bottom or top of channel or mesa, respectively, to film thickness at the planar portions of the wafer. One conventional method of controlling the target atom path is by locating collimators within the field between the target and substrate wafer. A conventional collimator system including a plurality of collimators is shown in Fig. 1 between a target 18 and a wafer 10. A collimator is preferably formed of a plurality of substantially planar surfaces of minimal thickness, which planar surfaces are provided perpendicular to the target and substrate surfaces. With such an orientation, target atoms travelling in substantially perpendicular paths will reach the substrate without contacting a collimator, but target atoms traveling along substantially oblique paths will contact the collimators and be blocked from reaching the wafer substrate.

A problem with conventional collimator systems is that, while providing good step coverage, they result in poor flat coverage uniformity across the wafer. As shown in Figs. 2 and 3, a point P₁ located directly beneath a collimator receives target atoms from a greater surface area of the target, as compared to a point P₂ located between the collimators, because the

point P_1 is subject to less blockage, or shadowing, by the collimators than is point P_2 . Thus, as shown slightly exaggerated in Fig. 3 for clarity, the deposited film tends to have a greater thickness under the collimators than in areas between the collimators. Varying the dimensions of the collimators and distance between the collimator and wafer will vary the location of greatest concentration of target atoms, but areas of disproportionate concentration still occur.

10 If a desired minimum thickness is to be obtained at point P_1 , for example, an excess amount of material needs to be deposited at P_1 in order to assure that the film thickness at P_2 will be adequate. This is disadvantageous because it wastes target material. The target is eroded faster than absolutely necessary and has to be replaced more often. The deposition of excess target material wastes time, energy, and increases the cost of production. Moreover, in some instances, the excess material near point P_1 has to be polished away or etched back in order to obtain uniform film thickness across the entire surface of the substrate. This also waste time, energy and resources.

20 One solution to the problem of poor flat coverage uniformity with collimators is to increase the pressure within the sputtering chamber. Increasing the pressure causes a greater number of collisions between the

target atoms as they approach the wafer, and thus the atoms scatter to a greater degree. Another solution to the problem of poor flat coverage uniformity with collimators is to increase the distance between the collimators and the wafer substrate. As with increased pressure, the greater distance allows more collisions and greater scattering of the target atoms. Additionally, increasing the distance between the collimators and wafer decreases the blockage or shadow effect that the collimators provide.

However, the problem with increasing the chamber pressure and/or increasing the distance between the collimator and substrate is that these solutions increase the incidence of target atoms contacting the substrate at oblique angles, thereby resulting in poor step coverage. Thus, the prior art solutions to poor flat coverage uniformity with collimators actually negate the purpose and advantages for which collimators are intended.

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SUMMARY OF THE INVENTION

It is therefore an object of the invention to provide a collimator system for use in a sputter apparatus that provides an improved combination of flat coverage uniformity and step coverage uniformity.

It is a further object of the present invention to provide an improved collimator system that can be used with conventional PVD sputter systems.

5 It is a further object of the present invention to reduce wafer fabrication time, cost and waste of resources by providing a more efficient film deposition process.

10 These and other objects are accomplished by the present invention which relates to a multiple tier collimator system for use in PVD sputtering of semiconductor wafers. In one embodiment of the invention, first and second tiers of collimators are provided between a target and wafer substrate. The two tiers are preferably hexagonal from a top perspective, 15 spaced from each other, and slightly staggered with respect to each other.

During a sputtering process, target atoms are dislodged from the target as result of charged ion particles contacting the surface of the target. The dislodged target atoms travel toward the wafer 20 substrate in substantially linear paths. The collimator system according to the present invention prevents target atoms from contacting the wafer at substantially oblique angles, thereby providing good step coverage uniformity over the surface of the wafer. 25 Additionally, the presence of more than one tier

prevents the localized build-up of target atoms on the wafer that occurs in conventional single tier collimators, thereby providing good flat coverage uniformity over the surface of the wafer.

- 5 The dimensions of the particular collimator tiers and their orientation relative to each other and the wafer may be varied to optimize flat coverage uniformity, step coverage uniformity and film deposition rate. Additionally, the dimensions and
- 10 relative orientations of the collimator tiers may be controlled to improve either flat coverage uniformity, step coverage uniformity or film deposition rate relative to the other properties.

BRIEF DESCRIPTION OF THE DRAWINGS

- 15 The below detailed description makes reference to the accompanying drawings, in which:

FIGURE 1 is an exploded perspective view of a conventional collimator system between a target and wafer;

- 20 FIGURE 2 is a cross-sectional view through Fig. 1 showing target atom paths from the target to the wafer;

FIGURE 3 is a cross-sectional view similar to Fig. 2 showing a profile of the film thickness deposition on the wafer;

FIGURE 4 is a perspective view of a multiple tier collimator system according to the present invention provided between a target and a wafer;

5 FIGURE 5 is a top view of the multiple tier collimator system shown in Fig. 4;

FIGURE 6 is a side cross-sectional view of a multiple tier collimator system shown in Fig. 4;

10 FIGURE 7 is a perspective view of an alternative embodiment of the multiple tier collimator system according to the present invention;

FIGURE 8 is a perspective view of a further embodiment of a multiple tier collimator system according to the present invention; and

15 FIGURE 9 is a perspective view of a further embodiment of a multiple tier collimator system according to the present invention.

DETAILED DESCRIPTION

The invention will now be described with reference to Figs. 4-9, which show various embodiments of a multiple tier collimator system. The collimator system of the present invention shall be described herein with regard to PVD sputtering of thin films onto semiconductor wafers. However, it is understood that the present invention relates specifically to the collimator system. Such a system may be used for

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sputtering films onto substrates other than semiconductor wafers. Moreover, it is understood that the collimator system according to the present invention may be used in various thin film deposition processes other than PVD sputtering.

Referring now to Figs. 4-6, there is shown a collimator system of the present invention located between a target 30 and a wafer substrate 32. Fig. 5 is a top view looking down through the collimator system, and Fig. 6 is a cross-sectional side view through the collimator system. Although not critical to an understanding of the present invention, target 30 and wafer 32 are generally planar, disc-shaped members oriented generally parallel to and concentric with each other. Target 30 is generally of a substantially larger diameter and greater thickness than wafer 32. In one embodiment of the invention, target 30 has a diameter of approximately 300mm and a thickness of approximately 20mm. For a target of these dimensions, the wafer substrate may have a diameter of approximately 200mm and a thickness of approximately 0.75mm. It is understood that both the shape and size of the wafer 30 and target 32 may vary in alternative embodiments of the present invention. Although only two are shown in Figs. 4-6, the surface of wafer 32 may include a number of channels 12 and mesas 14 thereon.

Target 30 may be formed of various materials, including for example, metals such as aluminum (Al), titanium (Ti), copper (Cu) and alloys or compounds of these materials.

5 Emission-inducing energy is applied to the active face of the target 30 in the form of, for example, a plasma containing accelerated argon ions. A power source (not shown) may be coupled to the target 30 in order to provide the source of the accelerated argon
10 ions. As is known in the art, confinement magnets (not shown) may also be provided adjacent the target for trapping the argon ions near the surface of the target, to thereby increase ion bombardment of the target.

 As result of the ion bombardment of the target 30,
15 target atoms are dislodged from the target and travel linearly away from the target, uniformly distributed about three-dimensional space. As previously described, it is desirable that those target atoms contacting the surface of wafer 32 travel along a
20 substantially perpendicular path between the target and wafer 32. Target atoms traveling along a substantially oblique path will result in relatively poor step coverage uniformity across the surface of wafer 32.

 In order to prevent target atoms traveling along
25 a substantially oblique path from reaching target 32, the present invention includes a multiple tier

collimator system including a first collimator tier 34 and a second collimator tier 36. Collimator tier 34 is comprised of a plurality of collimators 34_i and collimator tier 36 is comprised of a plurality of collimators 36_i. In a preferred embodiment, a particular collimator 34_i is identical to each of the other collimators in tier 34 and is identical in configuration to each of the collimators 36_i in tier 36. It is understood however, that in alternative embodiments of the present invention, a collimator 34_i of collimator tier 34 may have a dissimilar size and/or configuration than other collimators 34_j of collimator tier 34. Additionally, a collimator 34_i of collimator tier 34 may have a dissimilar size and/or configuration than a collimator 36_j of collimator tier 36.

In order to ensure that the collimators are effective over the entire surface of wafer 32, collimator tiers 34 and 36 are preferably concentric with and larger than wafer 32. In one embodiment of the invention, collimator tiers 34 and 36 may have a radius that is roughly 3 inches greater than that of the wafer 32. Therefore, where the wafer has a diameter of approximately 200mm, the collimator tiers 34 and 36 may have an approximate diameter of 300mm. It is understood that the relative sizes of the collimator tiers and the wafer may vary in alternative

embodiments provided that the collimator tiers are larger than the wafer.

Collimators 34_i and 36_i in one embodiment of the present invention have a hexagonal cross-section taken
5 from a perspective perpendicular to the surface of wafer 32. The walls separating each of the collimators 34_i and 36_i are preferably as thin as possible, such as for example, 2mm. In one embodiment of the invention, collimator tier 34 is separated from collimator tier 36
10 by a distance d_1 (Fig. 6) of 0.5mm. In this embodiment, each of the six planer surfaces comprising a particular collimator 34_i in collimator tier 34 may have a width d_2 of 10mm and a height d_4 of approximately 7mm. Similarly, each of the six planer surfaces comprising
15 a particular collimator 36_i of collimator tier 36 may have a width d_3 of 10mm and a height d_5 of 7mm.

As shown in Fig. 5, tier 34 and tier 36 are preferably overlapping but staggered with respect to each other taken from a perspective perpendicular to
20 the surface of wafer 32. In one embodiment of the invention, tier 34 may be staggered by 25% with respect to tier 36. The 25% stagger is obtained by moving 25% up along a first, vertical portion of the hexagon and then 25% diagonally across a second, adjacent portion
25 of the hexagon. Therefore, for the above-described dimensions, tier 34 will be offset from tier 36 by a

distance d_6 (Fig. 6) equal to 2.5mm. It is understood that the staggering of one tier with respect to the other may be lesser or greater than 25% in alternative embodiments.

5 In a preferred embodiment, the bottom collimator 36 may have a lower surface that is spaced a distance d_7 (Fig. 6) of approximately 20mm away from the surface of wafer 32. While the distance between the target and the upper surface of collimator tier 34 is not as
10 critical as the distance between the wafer 32 and the lower surface of collimator tier 36, the overall distance between target 30 and wafer 32 will affect the deposition rate for the process. Therefore, the distance between the target 30 and the wafer 32
15 preferably ranges between 50mm and 100mm, and the distance between target 30 and an upper surface of collimator tier 34 preferably ranges between 10mm and 50mm.

 A multiple tier collimator system having the above
20 described dimensions d_1 through d_7 has been found to yield a film deposition 38 having a particularly good combination of flat coverage uniformity and step coverage uniformity. As shown in Fig. 6, the thickness of film 38 across the surface of wafer 32 is relatively
25 uniform. Moreover, as described in the Background of the Invention section, excess deposition of the target

was necessary in conventional systems to ensure that each region of the wafer received at least a minimum required film thickness. By providing improved flat coverage uniformity, the collimator system according to
5 the present invention makes more efficient use of a target by providing the required minimum film thickness across the entire surface of the wafer without excess film deposition and excess erosion of the target. Similarly, only minimal polishing or etching, if any,
10 is required. Therefore, the present invention provides a saving in time, energy and resources.

It is further understood that each of the dimensions d_1 through d_7 may be varied in alternative embodiments of the invention, both absolutely and with
15 respect to each other. Generally, the distance d_1 between collimator tier 34 and collimator tier 36 may vary from 0.5mm to 5mm; the width d_2 of a collimator 34, and width d_3 of a collimator 36, may vary from 5mm to 20mm; and the height d_4 of a collimator 34, and height
20 d_5 of a collimator 36, may vary from 5mm to 20mm. The offset d_6 of collimator tier 34 from collimator tier 36 may vary from 0% to 50% of the width of a collimator 34, or 36, and a lower surface of collimator tier 36 may be located a distance d_7 away from wafer 32 that is between
25 10mm and 50mm.

Another consideration in providing the dimensions d_1 through d_7 is the rate of deposition of the target on the wafer. In general, as d_1 and d_3 increase, the deposition rate increases. As d_4 and d_5 increase, the deposition rate decreases. Therefore, along with step coverage uniformity and flat coverage uniformity, film deposition rate is also a factor relevant to determining the optimal dimensions for the collimators 34_i and 36_i. The dimensions of the collimators 34_i and 36_i may be varied to emphasize either step coverage uniformity, flat coverage uniformity, or film deposition rate over the other properties.

Up to this point, the multiple tier collimator system according to the present invention has been described as having two tiers. However, as shown in the alternative embodiment of Fig. 7, the present invention may include collimator tiers 40₁, 40₂,... up to 40_n, where in a preferred embodiment n is no greater than 5. It is contemplated, however, that n may be greater than 5 in alternative embodiments. The length and width of each of the six planar surfaces comprising a collimator shown in Fig. 7 preferably has the same dimensional ranges as recited above for collimator tiers 34 and 36 described with regard to Figs. 4-6. Similarly, the spacing between and the offset of adjacent tiers in Fig. 7 may have the same

dimensional ranges as recited above for collimator tiers 34 and 36 described with regard to Figs. 4-6. Finally, the lower tier 40, may have a lower surface that is spaced from the wafer 32 over a range of distances similar to that recited with respect to d, in Fig. 6.

It is further understood that the collimators comprising the collimator tiers may be formed of shapes other than hexagons. For example, Fig. 8 discloses a multiple tier collimator system similar to that shown in Fig. 4, with the exception that the shape of the individual collimators 42 are rectangular when viewed from a perspective perpendicular to the surface of wafer 32. Similarly, Fig. 9 discloses a multiple tier collimator system similar to that disclosed in Fig. 4, with the exception that collimators 44 are triangular when viewed from a perspective perpendicular to the surface of wafer 32. The dimensions of collimators 42 and 44 shown in Figs. 8 and 9, and the relative orientation of the collimator tiers to each other and to wafer 32, may be similar to the dimensional ranges disclosed for collimators 34, and 36, described with regard to Figs. 4-6. It is further understood that the collimator tiers according to the present invention may be comprised of various other geometric shapes when viewed from a perspective perpendicular to the surface

of wafer 32. As a further example, a collimator tier may be comprised of a plate with a plurality of circular, or other geometric-shaped, openings formed in the plate. Moreover, it is contemplated that different
5 collimator tiers within a single collimator system may be comprised of different geometric shapes and sizes.

The invention has been described thus far as including first and second collimating tiers residing in distinct, non-overlapping planes. However, in a
10 further embodiment of the present invention, the collimator system may be comprised of a single tier of collimators having a first group of coplanar collimators interspersed with a second group of coplanar collimators, where the first and second groups
15 reside in different but overlapping planes taken from a perspective parallel to the surface of wafer 32. It is further understood that more than two groups of collimators may be provided to reside in different but overlapping planes. Additionally, more than one tier
20 of collimators may be provided where one or more of the tiers is comprised of groups of collimators that reside in different but overlapping planes.

Although the invention has been described in detail herein, it should be understood that the
25 invention is not limited to the embodiments herein disclosed. Various changes, substitutions and

modifications may be made thereto by those skilled in the art without departing from the spirit or scope of the invention as described and defined by the appended claims.

We Claim:

1. A collimator system for use in a physical vapor deposition process to prevent dislodged target particles from a target from contacting a surface of a substrate at substantially oblique angles, the collimator system comprising:

a first tier capable of being provided between the target and substrate, with said first tier provided substantially parallel to the surface of said substrate, said first tier including a plurality of collimators; and

a second tier capable of being provided between the target and substrate, with said second tier provided adjacent said first tier and being substantially parallel to said first tier, said second tier including a plurality of collimators.

2. A collimator system as recited in claim 1, wherein the substrate comprises a semiconductor wafer.

3. A collimator system as recited in claim 1, wherein each collimator of said plurality of collimators has a hexagonal cross section.

4. A collimator system for use in a physical vapor deposition process to prevent dislodged target

particles from a target from contacting a surface of a substrate at substantially oblique angles, the collimator system comprising a plurality of collimator tiers, each tier of said plurality of collimator tiers including a plurality of adjacent collimators, said each tier provided with major surfaces generally parallel to each other and capable of being provided parallel to the surface of the substrate, and said each tier overlapping each other tier from a perspective perpendicular to said major surfaces.

5. A collimator system as recited in claim 4, wherein said plurality of tiers comprises greater than or equal to two tiers and less than or equal to two five tiers.

6. A collimator system as recited in claim 4, wherein said plurality of tiers comprises two tiers.

7. A collimator system as recited in claim 4, wherein said each tier overlaps each other tier such that a collimator from a first tier of said plurality of tiers is staggered with respect to a closest collimator of a second tier of said plurality of tiers adjacent to said first tier.

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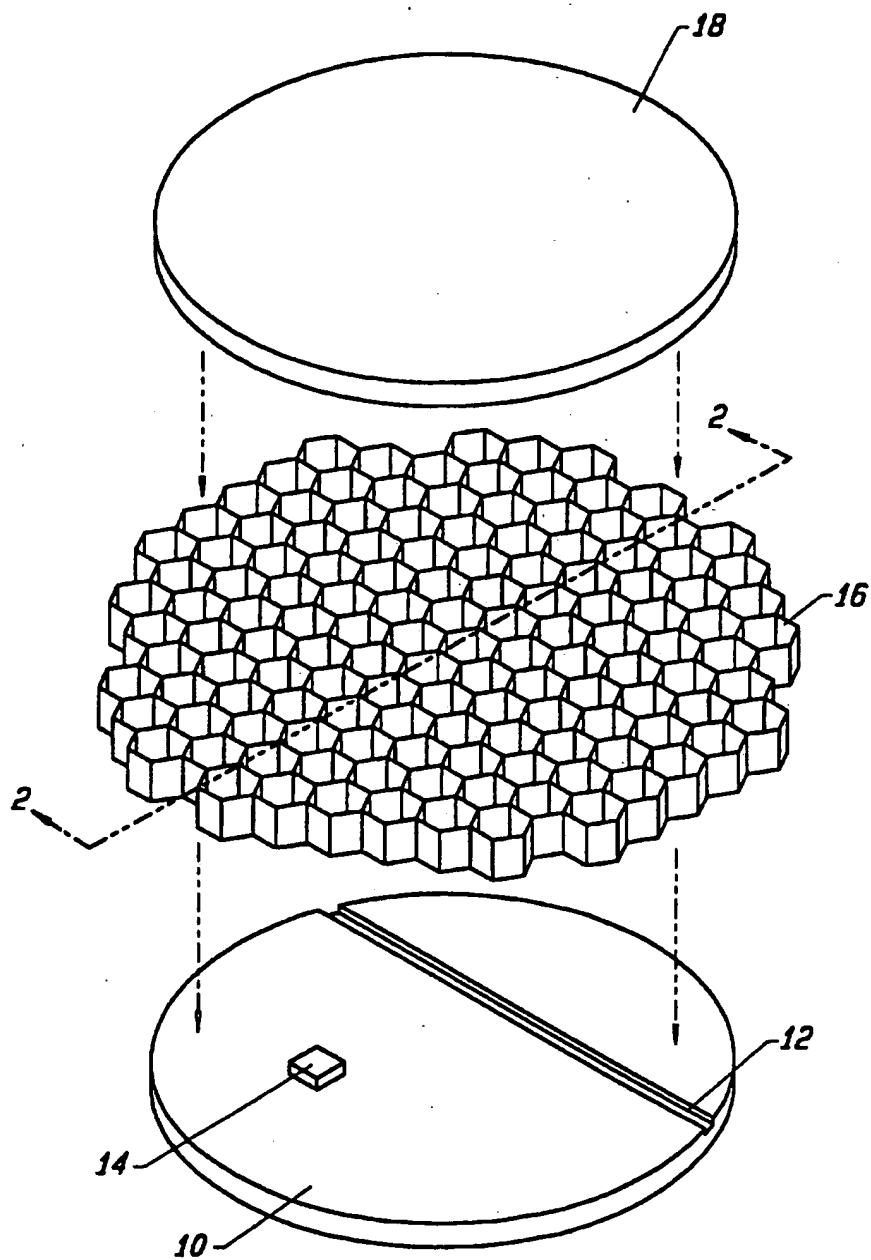


FIG. 1
(PRIOR ART)

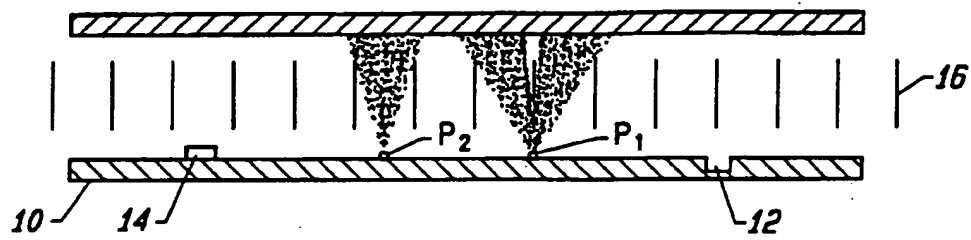


FIG. 2
(PRIOR ART)

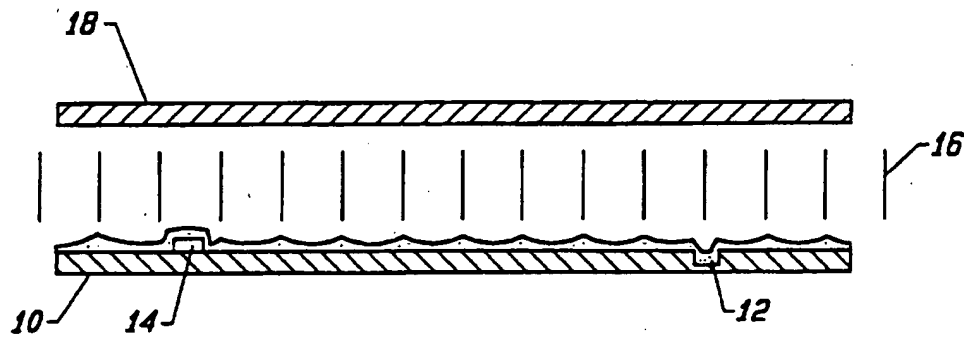


FIG. 3
(PRIOR ART)

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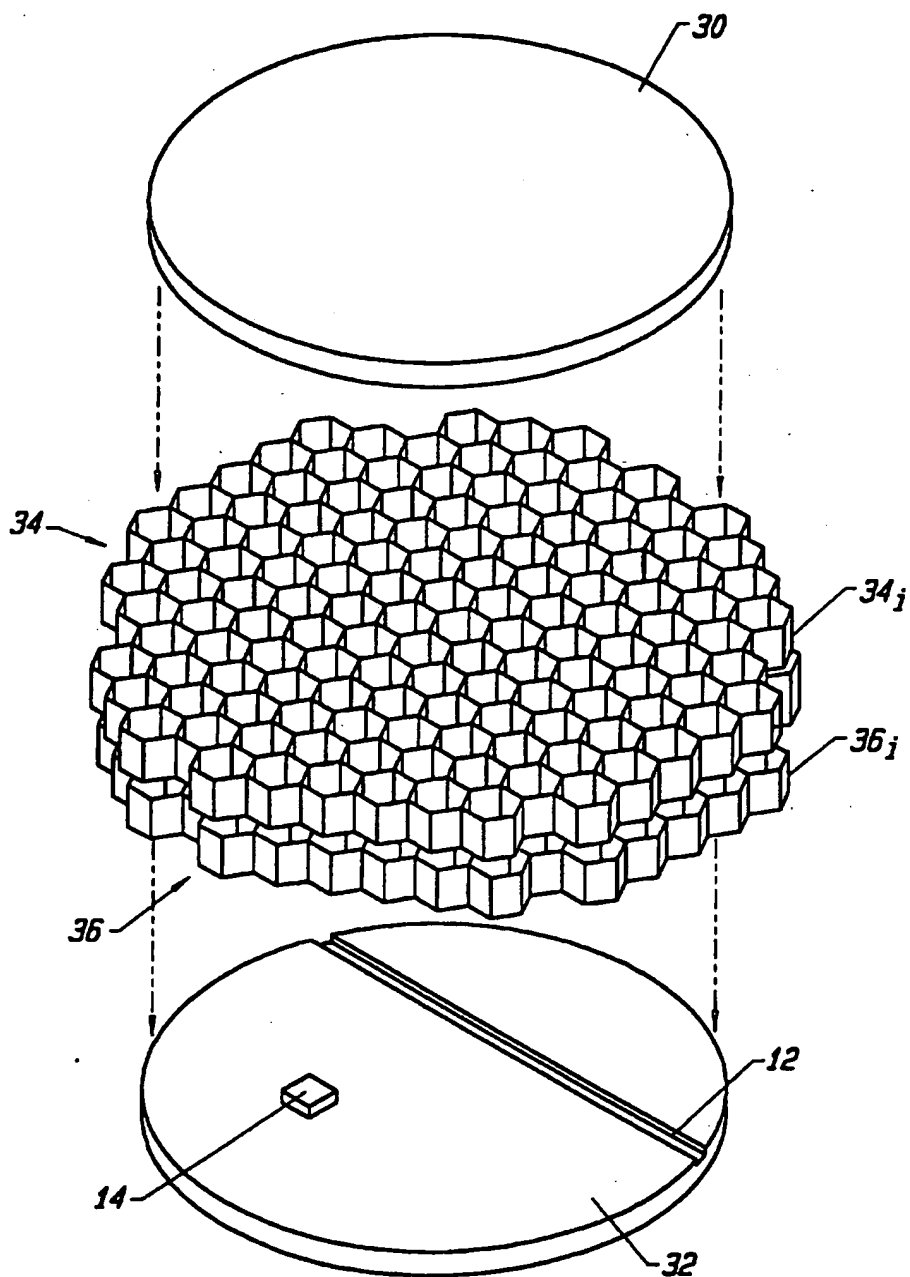


FIG. 4

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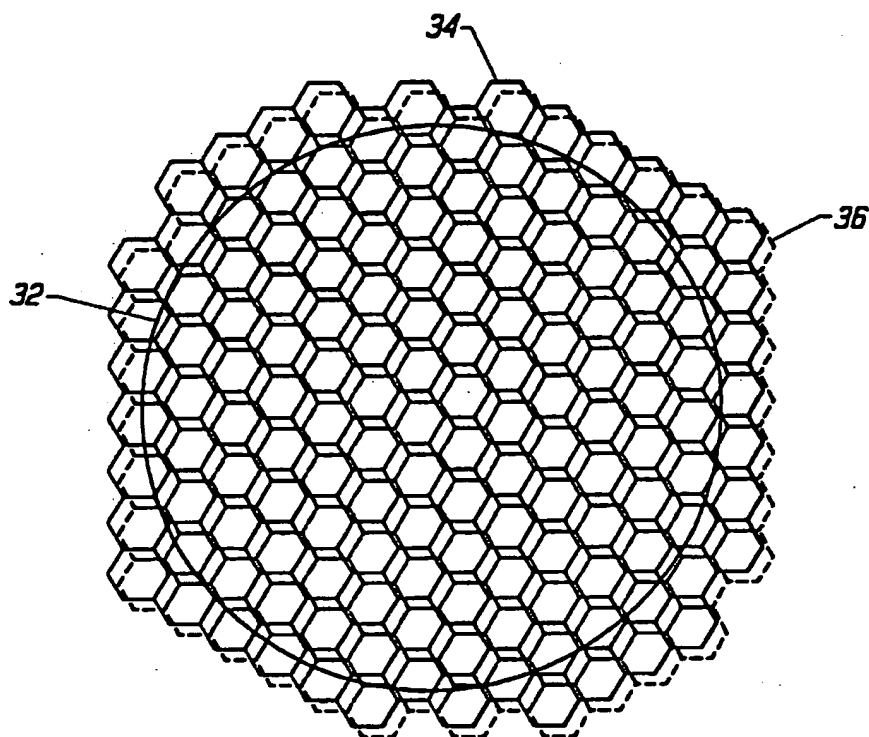


FIG. 5

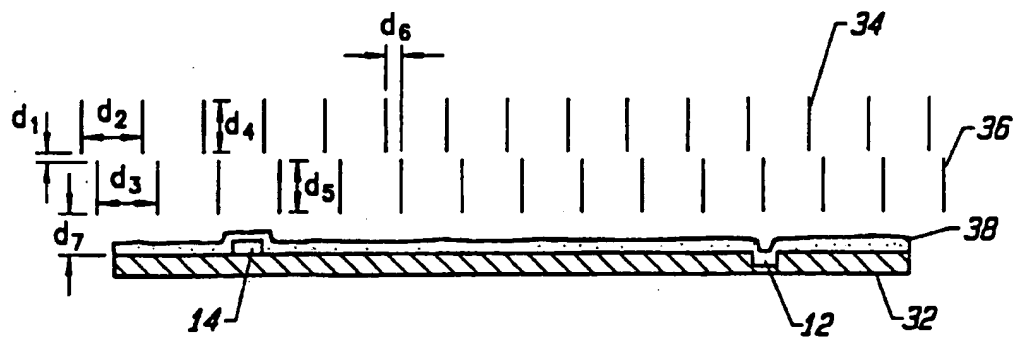


FIG. 6

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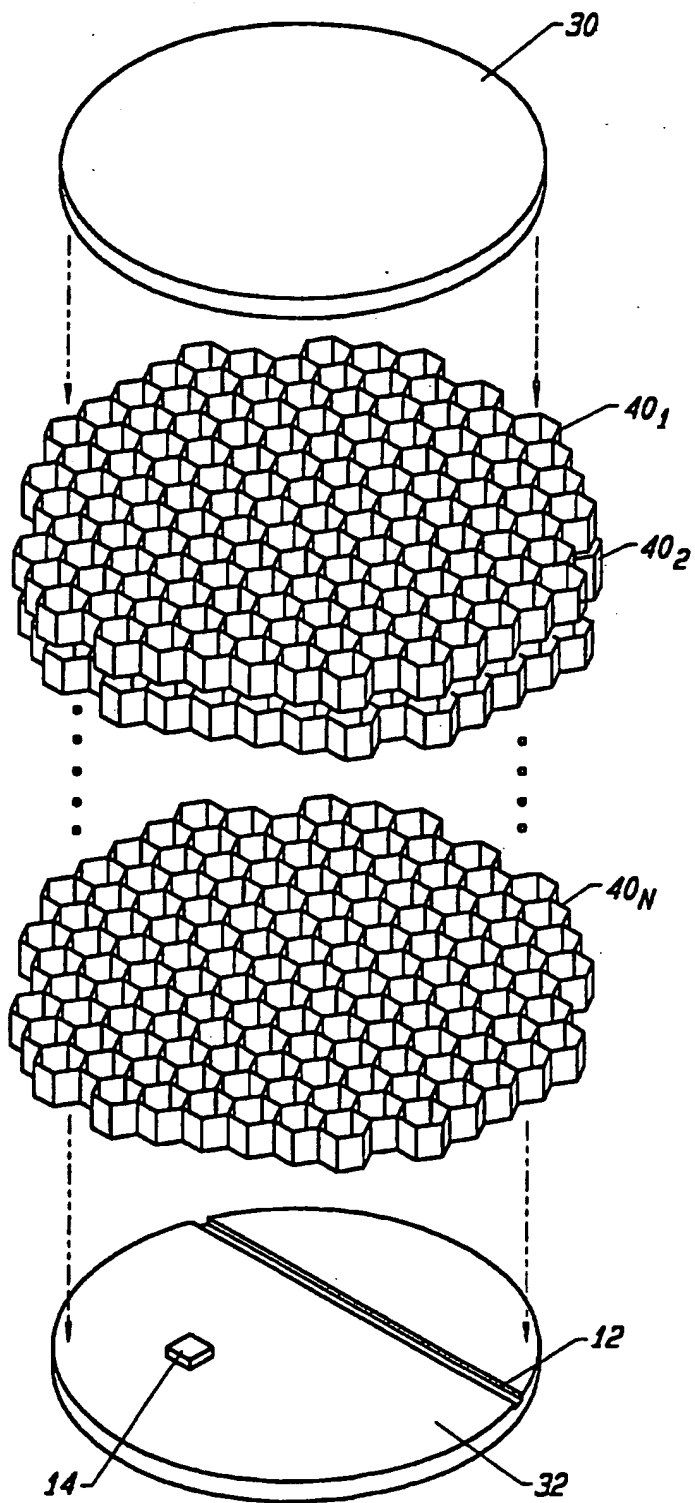


FIG. 7

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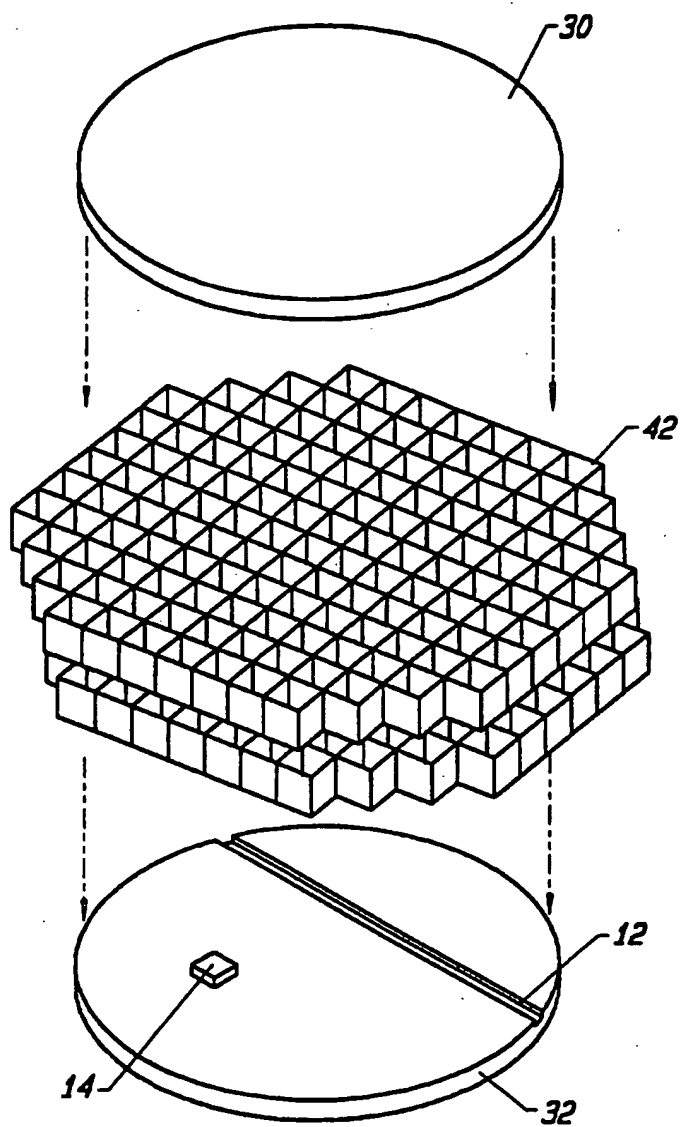


FIG. 8

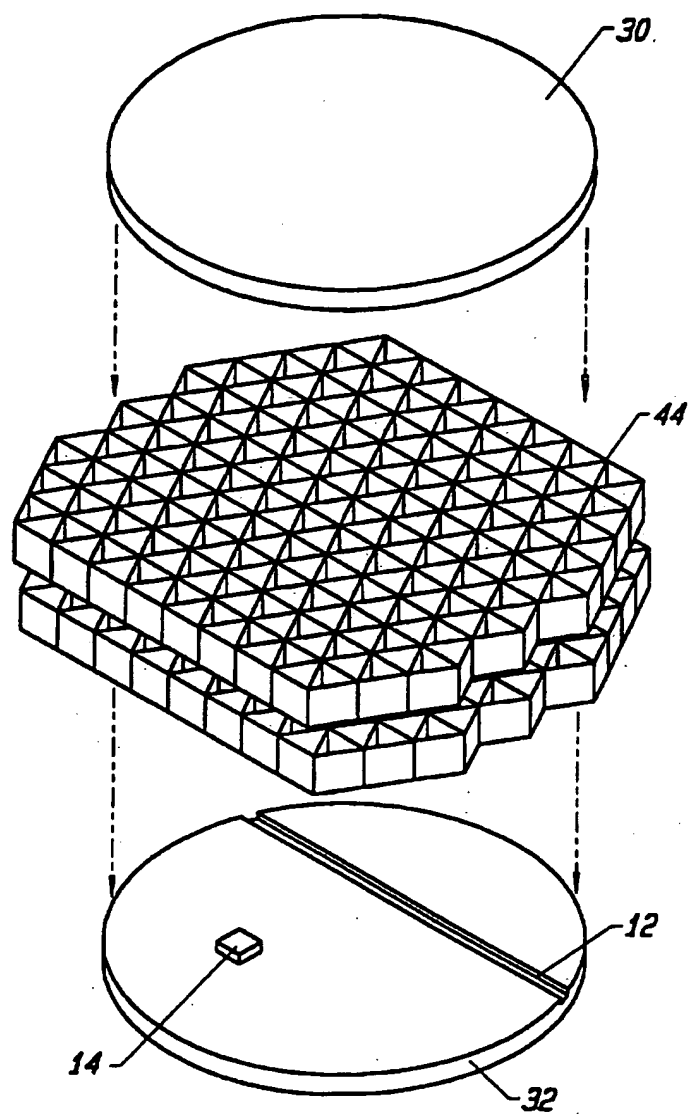


FIG. 9

INTERNATIONAL SEARCH REPORT

International Application No
PC/US 96/00572

A. CLASSIFICATION OF SUBJECT MATTER

IPC 6 H01J37/34

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC 6 H01J G21K

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
P,Y	EP,A,0 682 125 (APPLIED MATERIALS INC) 15 November 1995 see column 2, line 14 - line 23 see column 3, line 21 - line 26 see column 5, line 30 - line 41 see column 5, line 55 - column 6, line 3 see figure 6 ---	1-6
Y	EP,A,0 606 745 (VARIAN ASSOCIATES) 20 July 1994 see column 1, line 37 - column 2, line 5 see column 6, line 49 - column 7, line 26 see figure 5C ---	1-6
A	EP,A,0 440 377 (VARIAN ASSOCIATES) 7 August 1991 see column 10, line 27 - line 36 see figure 14 ---	1
-/-		

☒ Further documents are listed in the continuation of box C.

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Date of the actual completion of the international search

31 May 1996

Date of mailing of the international search report

12.06.96

Name and mailing address of the ISA

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Authorized officer

Capostagno, E

INTERNATIONAL SEARCH REPORT

Inter- national Application No
PC1/US 96/00572

C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT		
Category	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	WO,A,93 13542 (MATERIALS RESEARCH CORP) 8 July 1993 see page 19, paragraph 2 - page 20, paragraph 2 see figure 7 ---	1,7
A	US,A,4 046 359 (GELLERT JOBST ULRICH) 6 September 1977 see column 2, line 62 - column 3, line 1 see figures 2,3 ---	7
A	US,A,4 238 685 (TISCHER PETER) 9 December 1980 -----	

INTERNATIONAL SEARCH REPORT

International Application No.
PCT/US 96/00572

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